

### SW Test Workshop Semiconductor Wafer Test Workshop

### Probe Card Test Solution for 5th Generation Mobile Communications



Norman Chunghwa Precision Test Tech

June 3-6, 2018

### Outline

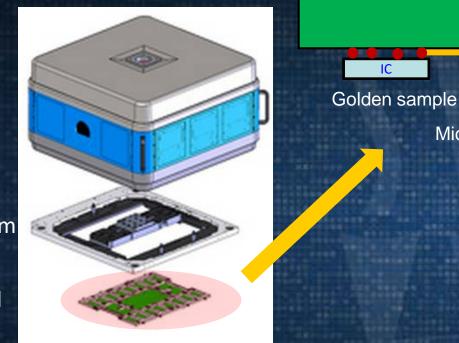
- Probe Card Test Solutions
- Pogo Pin Design for 28GHz Application
- The Loss Factors of T-Line & DK/DF Extraction
- Measurement and Simulation Correlation
- Conclusion

## **Probe Card Test Solution I**

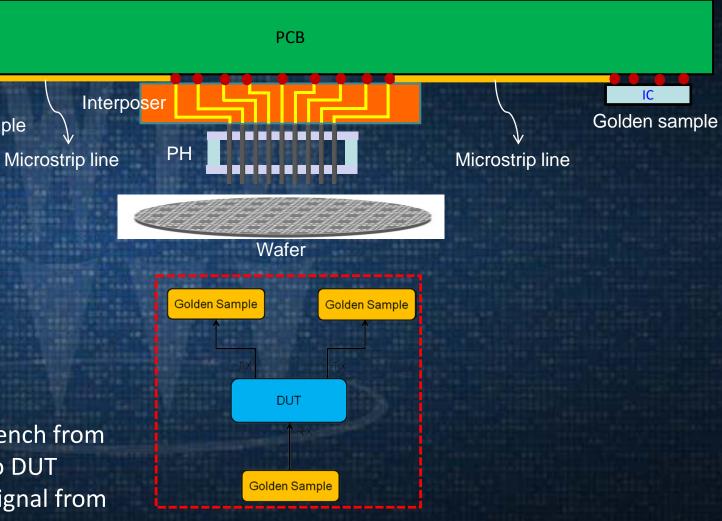
ATE

Bridge Beam

Probe Card



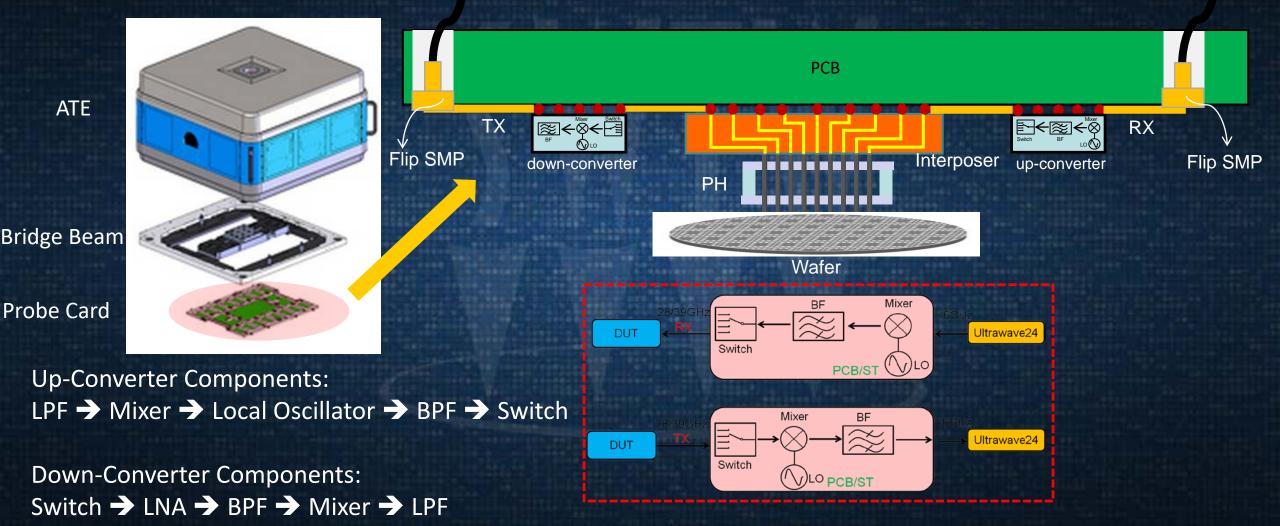
Golden Sample as an Ideal Instrument: The best-performance chips verified in the bench from Socket which can transmit good SNR signal to DUT and also work as a good receiver to take TX signal from DUT.



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### **Probe Card Test Solution II**



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# **Impedance Control on Probe Pattern**

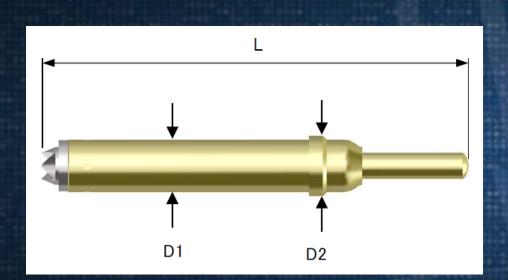
#### DFT should take impedance continuity of probe pattern into consideration

Key Factors of Impedance Control		Variables of Probe Pattern			
		Bandwidth			
(1)GND Probe Quantities $\rightarrow$		No GND Probe	2 GND Probe	4 GND Probe	
<u> </u>	O GND Probe 4 GND Probe	*	**	***	
2 Probe Pitch		X = 0.8mm	X = 0.5mm	X = 0.4mm	
		*	**	***	
③Probe Length	l e	Length =3.5mm	Length = 3mm	Free Length = 2.4mm	
		*	**	***	
		Type A(0.24mm)	Type B(0.26mm)	Type C(0.3mm)	
④Probe Radius		*	**	***	

Performance:  $\star$  Bad  $\star \star$  Medium  $\star \star \star$  Good

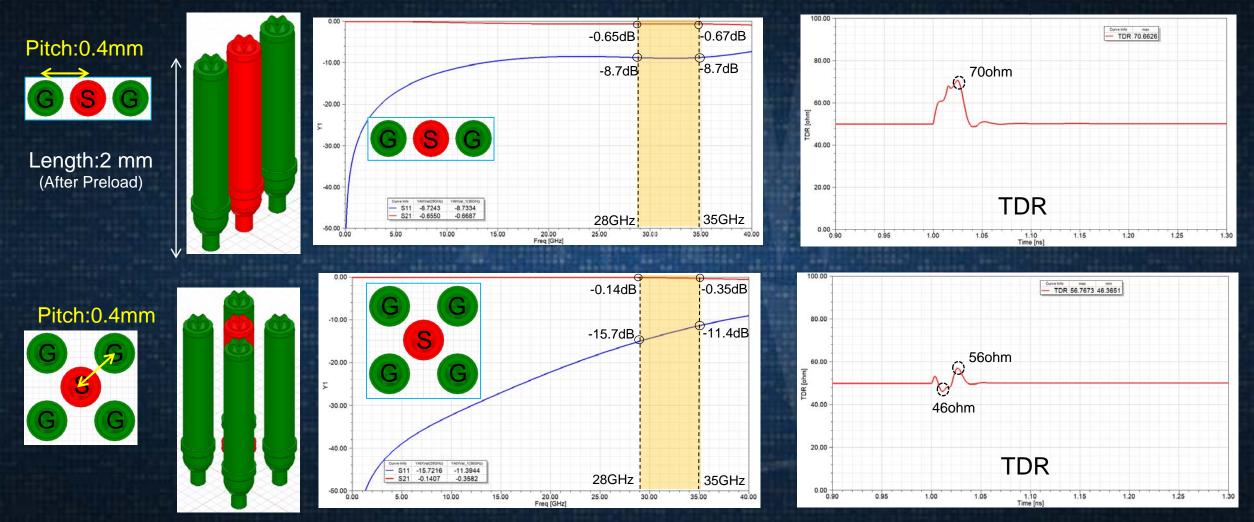
Refer to 2017 SWTW" Probe Pattern Design for Low-Cost and High-Speed Loopback Test"

# **28GHz Pogo Pin Specs**



Mechanical Spec.					
Pitch	0.4 mm				
Barrel Dia (D1/D2)	Ф0.3/0.34 mm				
Free/Operating Length	2.4/2 mm				
Operating Stroke	0.4 mm (0.25+0.15)				
Spring Force	16±4 gf				
Tip Style	Crown				
Electrical Characteristics					
Resistance @ Initial	60mOhm(AVR)				
Current Capacity	1.8A Max @ Room Temp.				
Self-Inductance	0.31 nH				

### **28GHz Pogo Pin Simulation**



# **The Loss Factors of the Transmission Line**

**T-Line Loss :** 
$$\alpha_{dB} = A_1 \sqrt{f} + A_2 f$$
 (*dB*/*in*

#### Conductive loss( $\alpha_c$ )

- Conductor loss refers to the T-Line series Resistance.
- T-Line Resistance is proportional to
- T-Line Resistance is inversely proportional to trace width.
- Metal Surface Roughness is also crucial.

• Dielectric loss refers to the T-Line shunt Conductance. • Dielectric loss is proportional to  $f_{req} \& \sqrt{\varepsilon_r} \& tan \delta$ 

$$\alpha_d = \frac{\pi \times f \times \tan \delta \times \sqrt{\varepsilon_r}}{3 \times 10^8}$$

Dielectric loss( $\alpha_d$ )

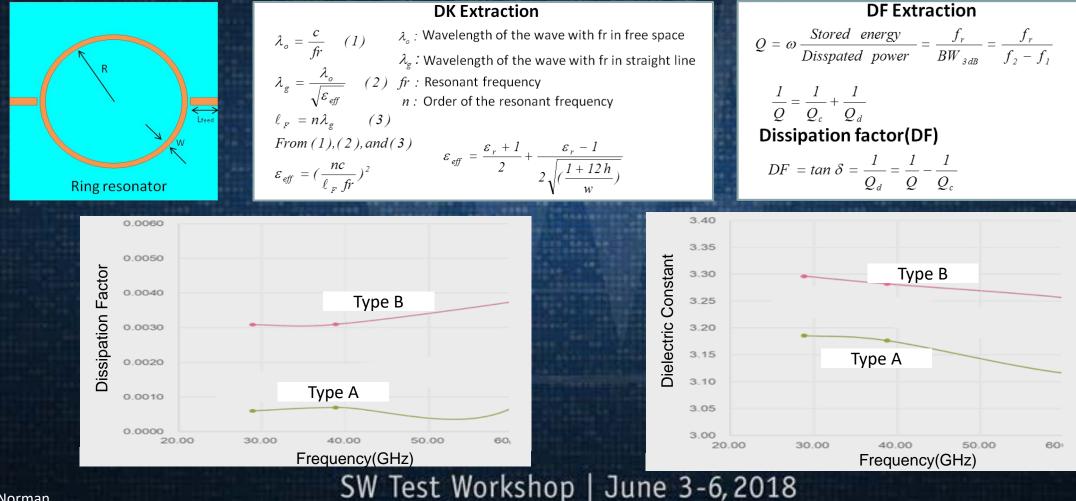
For 5G, we need low and flat DK/DF vs. Freq. due to 2 reasons:

- 1. 28GHz is a very high Freq., a big weighting in this loss formula.
- 2. DK/DF are Freq. dependent & 850 MHz Channel BW in 5G.
- → Keep channel power flatness & Avoid wideband signal dispersion due to different Vp.

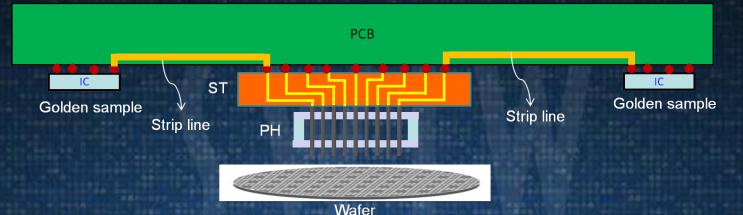
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# **PCB DK/DF Extraction**

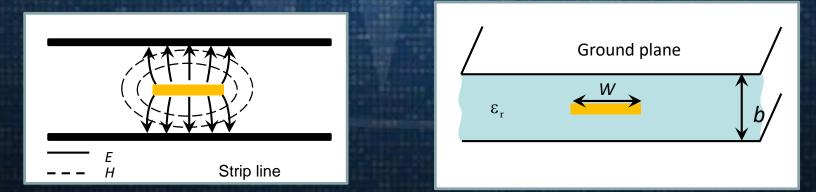
 M-Line Ring Resonator: Two-port gap-coupled Ring method to extract the PCB material's DK and DF.



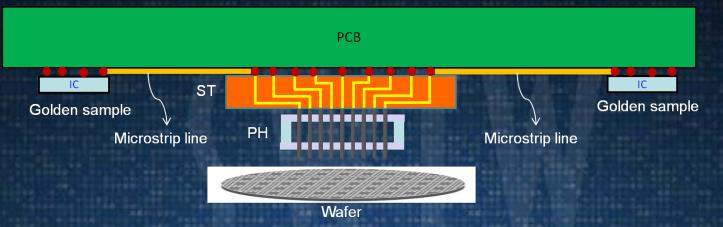
# **Transmission Line Structure-Strip line**



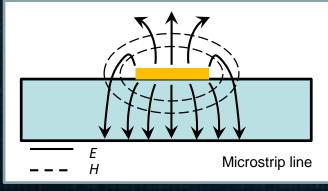
- Usual Mode: TEM mode due to two conductors with a homogenous dielectric ("Keff" is equal to ɛr.).
- High Order TE/TM Modes: Asymmetry is introduced between two GND planes, particularly in mmWave Freq.
- GND Stitch Via: Used to eliminate high order mode, an over-moded phenomenon.

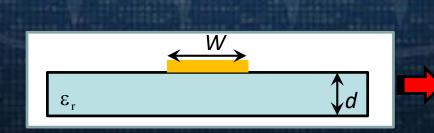


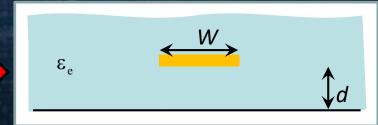
# **Transmission Line Structure-Microstrip line**



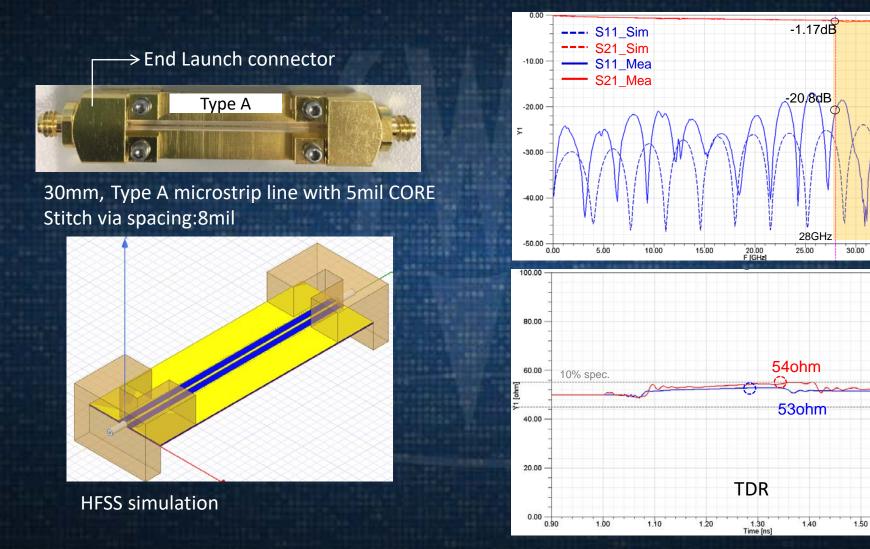
- Usual Mode: Complicated interface results in different Vp in the air and inside the dielectric. Quasi-TEM mode due to very thin dielectric, just like static case.
- Above the signal is air, effective dielectric constant :1<εe< εr.
- High Order Mode: Eliminate it by avoiding trace transverse discontinuity (bends, junction return path and step trace width change).







# **MS Line Simulation and Measurement (Type A)**



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-1.38dB

18.3dB

35GHz

40.00

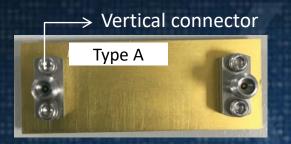
35 00

Curve Info TDR\_Mea TDR\_Sim

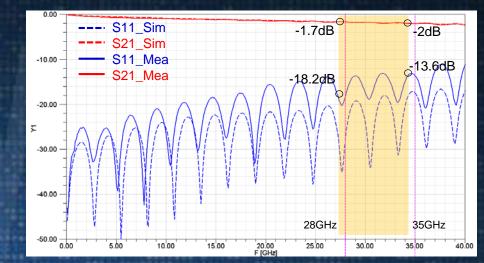
1.60

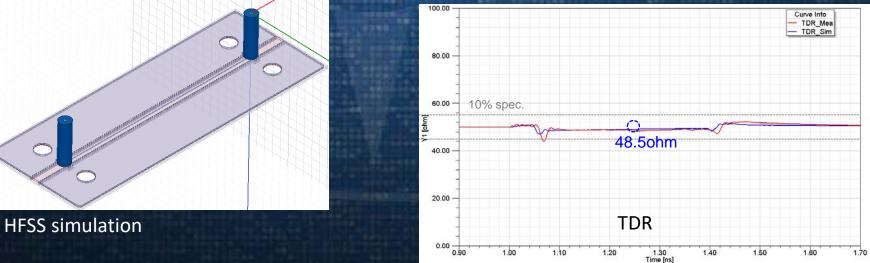
1.70

# Strip line Simulation and Measurement (Type A)

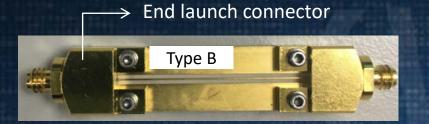


30mm, Type A strip line with 5mil CORE & 5mil PP Stitch via spacing:8mil

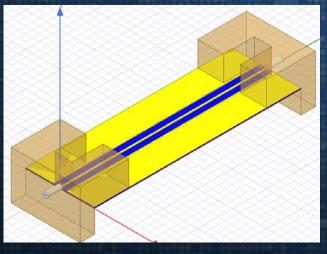


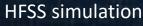


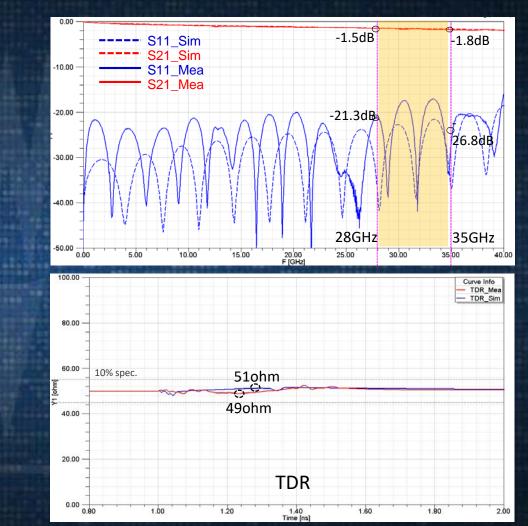
# **MS Line Simulation and Measurement (Type B)**



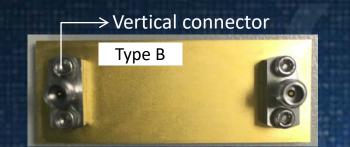
30mm, Type B microstrip line with 4mil CORE Stitch via spacing:8mil



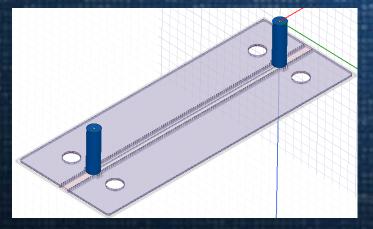




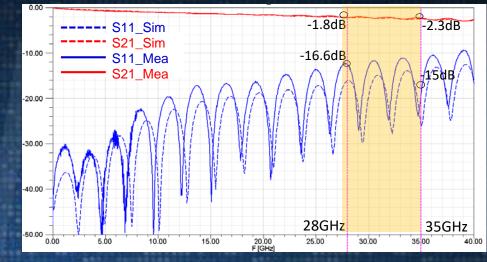
# **MS Line Simulation and Measurement (Type B)**

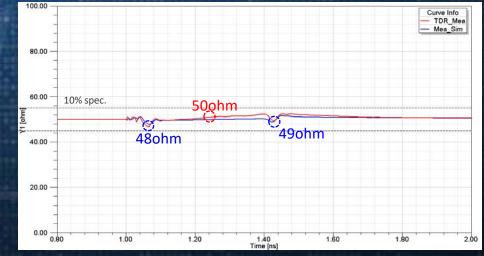


30mm, Type B strip line with 4mil CORE & 3.5mil PP Stitch via spacing:8mil



**HFSS** simulation





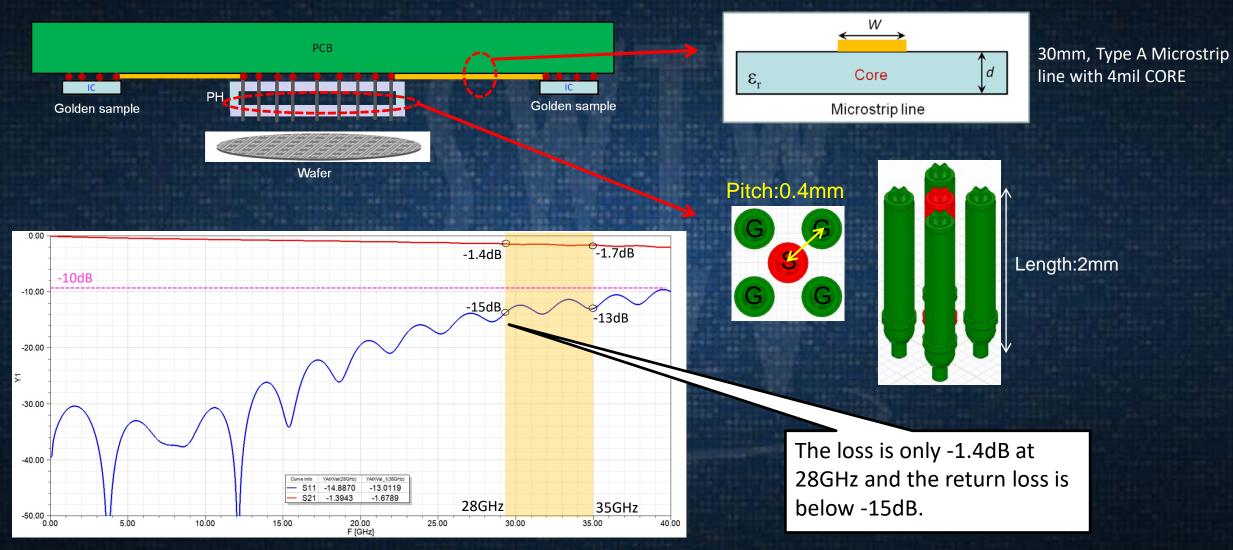
# **Correlation Summary**

Structure	MS Line	e (30mm)	Strip Line (30mm)		
Material	ТуреА	ТуреВ	ТуреА	ТуреВ	
S21@ 28GHz	-1.2dB	-1.5dB	-1.7dB	-2.2dB	
S11@ 28GHz	-20.8dB	-21.3dB	-18.2dB	-16.6dB	
Performance	**	*	**	*	

• For the same material, Microstrip line has lower loss than Stripline:

- ① At 28GHz, dielectric loss dominates the total power loss.
- ② Microstrip line has part of the electromagnetic field line in the air with lower loss.
- Same transmission line structure in different materials: Low DF indeed has lower power loss.

### **28GHz Probe with PCB simulation**



# Conclusion

#### • Probe Design

 For 28GHz probe design, there are 4 key factors to optimize the probe pattern for high performance, and we proposed a best design for 28GHz.

(1)GND Probe Quantities (2)Probe Pitch (3)Probe Length (4)Probe Diameter

### PCB T-Line Correlation

 After we put extracted DK/DF back to simulation, the correlation results are very close for both Microstrip line and Stripline.

- For the same material, Microstrip line has lower loss than Stripline.
- For the same trace structure on different material, low DF has lower power loss.
- 28GHz Probe Card Solution

After the performance optimization and carefully correlation, we provide the best
Probe Card Test Solution of the cascaded Pogo pin + Microstrip Line + Type A lower
DK/DF material.